

SEMICONDUCTOR®

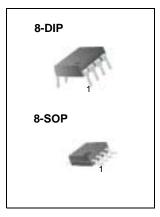
LM311 Single Comparator

Features

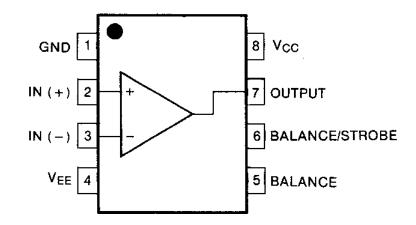
- Low input bias current : 250nA (Max)
- Low input offset current : 50nA (Max)
- Differential Input Voltage : ±30V
- Power supply voltage : single 5.0V supply to ± 15 V.
- Offset voltage null capability.
- Strobe capability.

Description

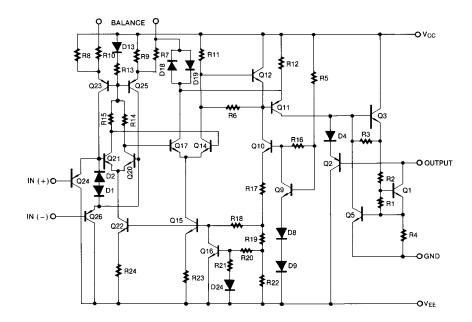
The LM311 series is a monolithic, low input current voltage comparator. The device is also designed to operate from dual or single supply voltage.



Internal Block Diagram



Schematic Diagram



Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Total Supply Voltage	Vcc	36	V
Output to Negative Supply Voltage LM311	Vo - Vee	40	V
Ground to Negative voltage	VEE	-30	V
Differential Input Voltage	VI(DIFF)	30	V
Input Voltage	VI	±15	V
Output Short Circuit Duration	-	10	sec
Power Dissipation	PD	500	mW
Operating Temperature Range	TOPR	0 ~ +70	٥C
Storage Temperature Range	TSTG	- 65 ~ +150	°C

Electrical Characteristics

(VCC = 15V, TA = 25° C, unless otherwise specified)

Parameter	Symbol	Conditions		Min.	Тур.	Max.	Unit
Input Offset Voltage	Vio	$R_S \leq 50 K \Omega$		-	1.0	7.5	mV
			Note 1	-	-	10	
Input Offset Current	lio			-	6	50	nA
			Note 1	-	-	70	
Input Bias Current	IBIAS			-	100	250	nA
			Note 1	-	-	300	
Voltage Gain	Gv	-		40	200	-	V/mV
Response Time	TRES		Note 2	-	200	-	ns
Saturation Voltage	VSAT	IO =50mA, VI ≤ -10mV		-	0.75	1.5	
		$\label{eq:VCC} \begin{array}{l} V_{CC} \geq 4.5 \text{V}, \ \text{V}_{EE} = 0 \text{V} \\ \text{I}_{O} = 8 \text{mA}, \ \text{V}_{I} \leq -10 \text{mV}, \end{array}$	Note 1	-	0.23	0.4	V
Strobe "ON" Current	ISTR(ON)	-		-	3	-	mA
Output Leakage Current	ISINK	ISTR =3mA, VI ≥ 10mV VO =15V, VCC=±15V		-	0.2	50	nA
Input Voltage Range	VI(R)	Note 1		-14.5 to 13.0	-14.7 to 13.8	-	V
Positive Supply Current	ICC	-		-	3.0	7.5	mA
Negative Supply Current	IEE	-		-	-2.2	-5.0	mA
Strobe Current	ISTR	-		-	3	-	mA

Notes :

1. $0 \le T_A \le +70^{\circ}C$

2. The response time specified is for a 100mV input step with 5mV over drive.



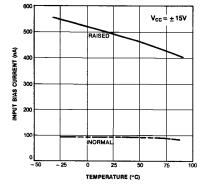


Figure 1. Input Bias Current vs Temperature

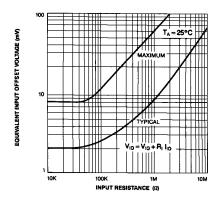


Figure 3. Offset Voltage vs Input Resistance

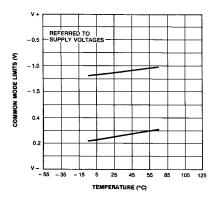


Figure 5. Common Mode Limits vs Temperature

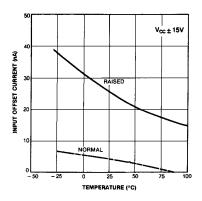


Figure 2. Input Offset Current vs Temperature

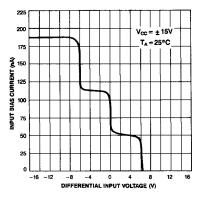


Figure 4. Input Bias Current vs Differential input voltage

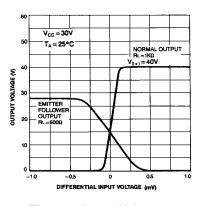


Figure 6. Output Voltage vs Differential input voltage

Typical Performance Characteristics (continued)

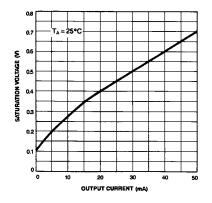


Figure 7. Saturation voltage vs Current

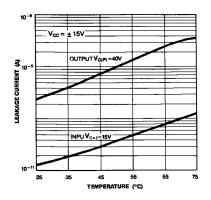


Figure 9. Leakage Current vs Temperature

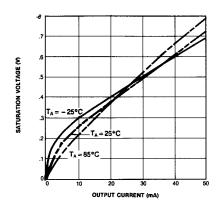


Figure 11. Current Saturation Voltage

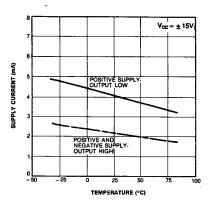


Figure 8. Supply Current vs Temperature

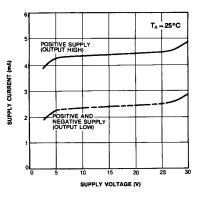


Figure 10. Supply Current vs Supply Voltage

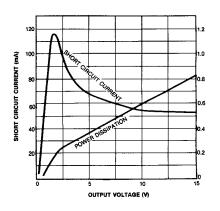
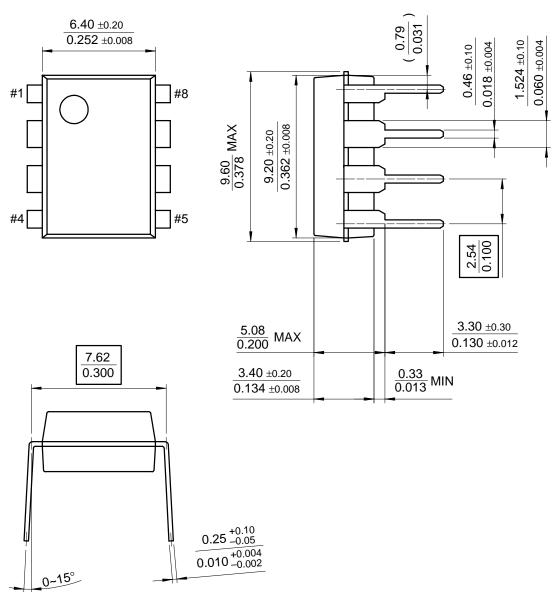


Figure 12. Output Limiting Characterstics

Mechanical Dimensions

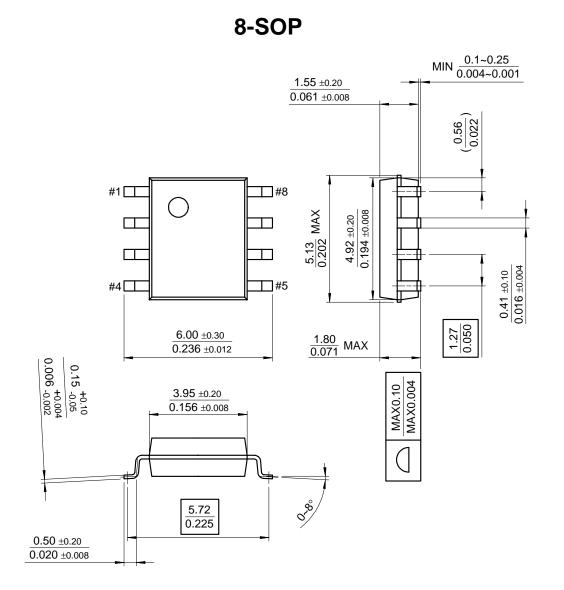
Package



8-DIP

Mechanical Dimensions (Continued)

Package



Ordering Information

Product	Number	Package	Operating Temperature
LM3	11N	8-DIP	0 ~ +70°C
LM3 ²	11M	8-SOP	0~+70 C

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- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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